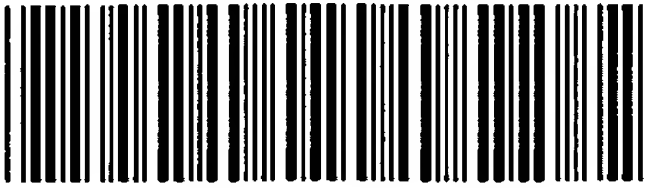


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/645,603	FUJII, TATSUYA	
	<b>Examiner</b>	<b>Art Unit</b>	
	Shawn Riley	2838	

SEARCHED			
Class	Subclass	Date	Examiner
323	268	12/5/2005	SR
	269 272		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR